



**International  
Standard**

**ISO 14880-3**

**Optics and photonics — Microlens  
arrays —**

**Part 3:  
Test methods for optical properties  
other than wavefront aberrations**

*Optique et photonique — Réseaux de microlentilles —*

*Partie 3: Méthodes d'essai pour les propriétés optiques autres que  
les aberrations du front d'onde*

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## Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of ISO document should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see [www.iso.org/directives](http://www.iso.org/directives)).

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This document was prepared by Technical Committee ISO/TC 172, *Optics and Photonics*, Subcommittee SC 9, *Laser and electro-optical systems*, in collaboration with the European Committee for Standardization (CEN) Technical Committee CEN/TC 123, *Lasers and photonics*, in accordance with the Agreement on technical cooperation between ISO and CEN (Vienna Agreement).

This second edition cancels and replaces the first edition (ISO 14880-3:2006), which has been technically revised.

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The main changes are as follows:

- Introduction revised;
- Reference documents and numbering updated.

A list of all parts in the ISO 14880 series can be found on the ISO website.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at [www.iso.org/members.html](http://www.iso.org/members.html).

## Introduction

This document specifies methods of testing optical properties, other than wavefront aberrations, of microlens arrays. Examples of applications for microlens arrays include three-dimensional displays, coupling optics associated with arrayed light sources and photo-detectors, enhanced optics for liquid crystal displays, and optical parallel processor elements<sup>[12][13][15][16]</sup>.

The testing of microlenses is in principle similar to testing any other lens. The same parameters need to be measured and similar techniques used. However, in many cases the measurement of very small lenses presents practical problems which make it difficult to use the standard equipment that is available for testing normal size lenses<sup>[15][16]</sup>.

The market in microlens arrays has generated a need for agreement on basic terminology and test methods. Standard terminology and clear definitions are needed not only to promote applications but also to encourage scientists and engineers to exchange ideas and new concepts based on common understanding.

This document contributes to the purpose of the series of ISO 14880 standards which is to improve the compatibility and interchangeability of lens arrays from different suppliers and to enhance development of the technology using microlens arrays.

Characteristic parameters are defined and examples of applications given in ISO 14880-1. It has been completed by a set of three other International Standards, i.e. ISO 14880-2, ISO 14880-3 and ISO 14880-4.

This document describes the measurement of 1) focal length, 2) coupling efficiency, 3) imaging quality and 4) focal spot positions.

The focal length of the microlens is defined more precisely in ISO 14880-1 as effective back (front) focal length.

The measurement of effective back (front) focal length is described in the body of this part of ISO 14880 and the use of an alternative technique, interferometry, is described in [Annex A](#).

Measurement of the focal length of an array of microlenses, using a confocal technique, is described in the main body and [Annex B](#).

Coupling efficiency and imaging quality are discussed in [Annex C](#).

Measurement of the focal spot positions of an array of microlenses in parallel, using the Shack-Hartmann technique, is described in [Annex D](#).

Wavefront aberrations and characteristics other than optical properties are specified in ISO 14880-2 and ISO 14880-4 and ISO/TR 14880-5.



# Optics and photonics — Microlens arrays —

## Part 3:

# Test methods for optical properties other than wavefront aberrations

## 1 Scope

This document specifies methods for testing optical properties, other than wavefront aberrations<sup>[1]</sup> of microlenses in microlens arrays. It is applicable to microlens arrays with very small lenses formed on one or more surfaces of a common substrate and to graded-index microlenses.

## 2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO 14880-1, *Optics and photonics — Microlens arrays — Part 1: Vocabulary*

ISO 10110-5, *Optics and photonics — Preparation of drawings for optical elements and systems — Part 5: Surface form tolerances*

## 3 Terms and definitions

For the purposes of this document, the terms and definitions given in ISO 14880-1 apply.

ISO and IEC maintain terminology databases for use in standardization at the following addresses:

- ISO Online browsing platform: available at <https://www.iso.org/obp>
- IEC Electropedia: available at <https://www.electropedia.org/>

## 4 Substrate test

The optical quality of the substrate contributes to the quality of the focal positions defined by the microlenses and shall be quantified in accordance with ISO 10110-5.

## 5 Microscope test method

### 5.1 Principle

The basic principle is to locate, by optical means, the surface of the microlens under test. The effective back (front) focal length is determined by measuring the axial displacement necessary to locate the focal position.

## 5.2 Measurement arrangement and test equipment

### 5.2.1 General

The testing of microlenses is similar in principle to testing larger lenses. In many cases however, the measurement of very small lenses presents practical problems which make it difficult to use standard equipment. In general, two optical techniques can be used. One is based on microscopy, the other is based on interferometry<sup>[2]</sup>.

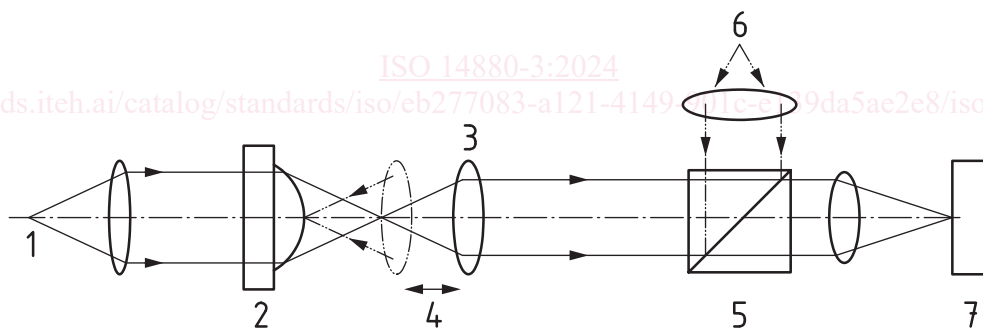
The first technique uses a microscope to locate, by focusing, the vertex of the microlens. The effective back (front) focal length is deduced from a measurement of the displacement necessary to refocus the microscope on the image of a distant source as shown in [Figure 1](#).

A focusing aid in the microscope such as a split-field focusing graticule enables the featureless vertex of a microlens to be more readily located when viewing with reflected light. For focal length measurements the distant point source may be the end face of an illuminated optical fibre or an illuminated test graticule. Tests may be performed with white light or monochromatic illumination.

The second technique uses wavefront sensing to locate the test surface or the centre of curvature. The location test may be carried out with the help of one of the following devices:

- Fizeau interferometer,
- Twyman-Green interferometer,
- lateral shearing interferometer, or
- Shack-Hartmann device.

These are more fully described in ISO 14880-2 and ISO/TR 14999-1<sup>[1][2]</sup>. One advantage of interferometry is that for strongly aberrated lenses, the variation in focal length with aperture radius can be readily deduced from the interference patterns. A disadvantage is that tests are restricted to the wavelength of the interferometer light source.



#### Key

- 1 distant point source
- 2 substrate and microlens producing focused spot
- 3 microscope objective
- 4 axial adjustment of microscope to locate lens surface and focus
- 5 beamsplitter
- 6 source for focus location on lens surface
- 7 imaging array

**Figure 1 — Collimated source and microscope used to measure the effective back or front focal length of a microlens**

[Clauses 5](#) to [9](#) concentrate on the microscope technique while an interferometric technique is described in [Annex A](#) and a Shack-Hartmann technique in [Annex D](#).



The confocal measurement of the effective focal lengths of lens arrays is described in [Annex B](#).

## 5.2.2 Test system

### 5.2.2.1 General

The test system consists of a microscope fitted with displacement transducers, suitable light source, test object, microscope video camera, monitor and image analyser (line intensity scan).

### 5.2.2.2 Microscope

A microscope fitted with a focusing aid such as a split-image rangefinder is required to enable focus settings to be made on a featureless surface such as the vertex of the microlens surface. The mechanical design shall allow the distant point source or test graticule to be placed below the stage carrying the test lens. Ideally, the test lens should be supported with no additional optical component such as a glass plate between it and the distant point source or test graticule. The displacement of the test surface relative to the microscope objective is measured with a calibrated displacement transducer.

The numerical aperture (NA) of the microscope objective shall be larger than the numerical aperture of the test lens at the focal point.

### 5.2.2.3 Light source

A light source emitting radiation in the band of wavelengths or at a specific wavelength required for the test shall be used. The properties of the light source shall be described in the test report.

White light can be provided by a quartz-halogen lamp in combination with a suitable aperture stop. Narrow band filters can be used where a restricted range of wavelengths is required. A laser or LED can be used for monochromatic illumination and higher intensities.

### 5.2.2.4 Test object (test graticule)

The distant point source can be approximated using the end face of an illuminated optical fibre. The distant point source shall be placed on axis with the lens and at an effectively large distance to enable the focal length to be determined.

Alternatively, the object may be a graticule. This enables the optical properties at particular spatial frequencies and field angles to be studied.

The detection of the focus spot may be susceptible to under-sampling by the detector array.

The distant point source or test graticule used shall be described in the documentation of the test report.

### 5.2.2.5 Image display

If the image generated by the microscope is relayed by a video camera to a video display, an electronic intensity display can be used to assist in locating the position of best focus. The intensity of the image at the detector shall be adjusted to maintain a linear response from the detector system.

### 5.2.2.6 Standard surfaces

A microlens of known focal length at a defined wavelength shall be used as a calibration artefact to verify the performance of the measurement system.

A step height artefact, for example two thin glass plates held together in optical contact to provide a step of known height, shall be used to verify the performance of the displacement measurement system.

### 5.2.2.7 Preparation

For consistent results the test equipment shall be maintained in a temperature-controlled environment, preferably at 20 °C and not exposed to vibration.

The optical surfaces to be tested shall be clean. Uncoated glass surfaces may be safely cleaned with alcohol and cotton wool. The cotton wool should be soaked in a very small amount of solvent before touching the surface and wiped only once across the optical surface before being discarded. This minimizes the chances of scratching the surface. Dust may be removed using a clean camel-hair brush or filtered compressed air.

Coated optical surfaces such as antireflection surfaces should be treated with great care and not cleaned unless absolutely necessary. They may be dusted using filtered compressed air.

Guidance should be sought on the correct use of solvents and cleaning materials.

## 6 Procedure

### 6.1 General

Clean the surface of the lens and substrate to be tested.

### 6.2 Measurement of effective back or front focal length

Standard instrument calibration procedures shall be carried out periodically and the calibration uncertainty estimated<sup>[4][9][10]</sup>.

Verify the performance of the test system by measuring, as described below, the effective back (front) focal length of the standard spherical surface and comparing the result with the known value.

The microscope is focused on the surface of the microlens and then displaced to focus on the image of a graticule or a point source placed at infinity. The best focus position for this image may be located using a camera and display with line scan to determine the displacement position at which the peak intensity in the image is greatest. The spatial resolution of the camera system shall be sufficient to resolve the image. The axial displacement is measured using the displacement transducer.

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### 6.3 Measurement of chromatic aberration

In general, microlenses are of relatively simple design and are not corrected for chromatic aberration. The focal length will vary with wavelength of illumination<sup>[11]</sup>.

With conventional lenses, a ray is deviated by refraction at the interface between two optical media with distinctly different refractive indices. The magnitude of the paraxial focal length for a single spherical surface of radius  $R$  is given by [Formula \(1\)](#):

$$f = R / [n_1(\lambda) - n_2(\lambda)] \quad (1)$$

where  $n_1$  and  $n_2$  are the refractive indices of the two media before and after the interface at a wavelength  $\lambda$ . The chromatic aberration of the lens is determined by the dispersion characteristics of the two media,  $n_1(\lambda)$  and  $n_2(\lambda)$ .

The conventional way of characterizing the dispersion of optical materials is by the Abbe number  $\nu$ , the definition of which includes values for the refractive index of the material at three wavelengths. For example